

## PATENT APPLICATION

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FORM PTO-1449	ATTY. DKT NO.	1-103-CON7	SER. NO.	10/499744
	APPLICANT	MAMITSU et al.		
	FILING DATE	Nov. 4, 2003	GROUP	2826

## REFERENCE DESIGNATION

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
DN	5,708,299	Jan. 13, 1998	Teramae et al		
	6,072,240	June 6, 2000	Kimura et al		
	5,248,853	Sep. 28, 1993	Ishikawa et al		
	5,801,445	Sep. 1, 1998	Ishihara et al		
	5,229,646	Jul. 20, 1993	Tsumura		
	4,558,345	Dec. 10, 1985	Dwyer et al		
	4,546,374	Oct. 8, 1985	Olsen et al		
	4,984,061	Jan. 8, 1991	Matsumoto		
	5,481,137	Jan 2, 1996	Harada et al.		
	4,827,082	May 2, 1989	Horiuchi et al		
DN	4,538,170	Aug. 27, 1985	Yerman		

## FOREIGN PATENT DOCUMENTS

## TRANSLATION

	DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO
DN	EP0660396	12/24/93	Europe					
	EP0450980	4/05/91	Europe					
	6-291223	10/94	JAPAN					
	3-20067	01/91	JAPAN					
DN	2146174	11/85	GB					

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

DN	Takamura, "Electronic Technology", pp. 56-59 (1999-5).
DN	Johnson et al., "Silicon Precipitate Nodule-Induced Failures of MOSFETS", ISTFA '91 (Nov. 11-15, 1991), pp. 161-165.
EXAMINER	DATE CONSIDERED
DN	8/4/04

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## REFERENCE DESIGNATION

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
PW	4,646,129	Feb. 24, 1987	Yerman et al		
	4,141,030	Feb. 20, 1979	Eisele et al		
	6,448,645	Sep. 10, 2002	Kimura		
	6,538,308	Mar. 25, 2003	Nakase		
	6,380,622	Apr. 30, 2002	Hirai		
	09/675,209	Filed Sept. 29, 2000	Suzuki		
PW	5,221,851	Jun. 22, 1993	Gobrecht et al.		

## FOREIGN PATENT DOCUMENTS

## TRANSLATION

	DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO
PW	4-249353	9/92	JAPAN					
	11-260979	09/99	JAPAN					
	4-27145	01/92	JAPAN					
	9-148492	06/97	JAPAN					
	4-12555	01/92	JAPAN					
	4-103150	04/92	JAPAN					
	60-137042	07/85	JAPAN					
	5-109919	04/93	JAPAN					
PW	61-166051	07/86	JAPAN					
	2-117157	05/90	JAPAN					
	63-102326	05/88	JAPAN					

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER	<i>[Signature]</i>	DATE CONSIDERED	8/14/04
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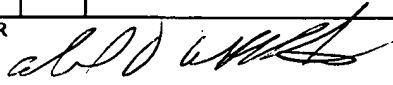
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
DN	5,990,550	Nov. 23, 1999	Umezawa		
	5,608,610	Mar. 4, 1997	Brzezinski		
	5,396,403	Mar. 7, 1995	Patel		
	5,293,301	Mar. 8, 1994	Tanaka et al.		
	5,641,997	June 24, 1997	Ohta et al.		
DN	5,789,820	Aug. 4, 1998	Yamashita		

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## TRANSLATION

	DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO
DN	60-235430	11/85	JAPAN					
	07-240432	9/95	JAPAN					
	8-45874	2/96	JAPAN					
	60-95947	05/85	JAPAN					
	61-265849	11/86	JAPAN					
	62-141751	06/87	JAPAN					
	63-096946	04/88	JAPAN					
	62-92349	4/87	JAPAN					
	62-287649	12/87	JAPAN					
	59-38734	09/84	JAPAN					
	01-228138	09/89	JAPAN					
	54-40569	03/79	JAPAN					
	61-251043	11/86	JAPAN					
DN	54-95183	07/79	JAPAN					

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER		
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## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
<i>on</i>	2002/0158333	Oct. 31, 2002	Teshima		
	S/N 10/201556	July 24, 2002	Hirano et al.		
	5726466	March 10, 1998	Nishitani		
	4,470,063	Sep. 4, 1984	Arakawa et al.		
<i>on</i>	5,708,299	Jan. 13, 1998	Teramae et al		

## FOREIGN PATENT DOCUMENTS

## TRANSLATION

	DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO
<i>on</i>	59-031042	02/84	JAPAN					
	07-038013	02/95	JAPAN					
	07-273276	10/95	JAPAN					
	08-191145	07/96	JAPAN					
	2000-91485	03/00	JAPAN					
	W098/12748	3/26/98	PCT					
	JP-A-5-283562 *	10/29/93	JAPAN				X	
	JP-A-6-349987 *	12/22/94	JAPAN				X	
	JP-A-7-45765 *	2/14/95	JAPAN				X	
	JP-A-11-186469 *	7/9/99	JAPAN				X	
	JP-A-2000-31351 *	1/28/00	JAPAN				X	
<i>PW</i>	JP-A-2001-118961 *	4/27/01	JAPAN				X	

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER	<i>CRD [signature]</i>	DATE CONSIDERED
		8/4/04